Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10731417	SINHA, AMIT
Examiner	Art Unit
Flores, Leon	2611

SEARCHED					
Class	Subclass	Date	Examiner		
375	322, 326, 316	2/7/2007	LF		
329	345, 346	2/7/2007	LF		

SEARCH NOTES				
Search Notes	Date	Examiner		
Consulted with SPE David Payne in regards to the patentability of the claims.	2/12/2007	LF		
Consulted with SPE Chieh Fan in regards to claim 7.	2/7/2007	LF		
Searched using NPL database (IEEE)	2/6/2007	LF		
Checked for possible Double Patenting.	2/6/2007	LF		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
			<u> </u>	

Part of Paper No.: 20070208